

Search Notes

Application/Control No.

10/541,974

Examiner

John E. Chapman

Applicant(s)/Patent under Reexamination

MESSER ET AL.

Art Unit

2856

SEARCHED

Class	Subclass	Date	Examiner
73	622		
	623		
	624		
	627		
310	334		
	336	3/19/2007	JC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner